

(PW)

Atty. Docket No. 4192.P053D2

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re Application of:  
Min-hwa Chin  
Application No.: 10/642,416  
Filed: August 15, 2003  
For: TRANSISTOR AND LOGIC CIRCUIT ON THIN  
SILICON-ON-INSULATOR WAFERS BASED ON  
GATE INDUCED DRAIN LEAKAGE CURRENTS

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

REQUEST FOR STATUS OF APPLICATION

Dear Commissioner:

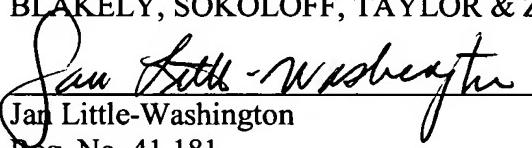
Please inform us on the current status of the above-referenced patent application.

If there are any further charges, please charge them to Deposit Account No. 02-2666.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Dated: 5/31/2005

  
Jan Little-Washington  
Reg. No. 41,181

12400 Wilshire Blvd.  
Seventh Floor  
Los Angeles, CA 90025-1026  
(206) 292-8600

FIRST CLASS CERTIFICATE OF MAILING

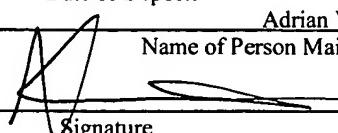
I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

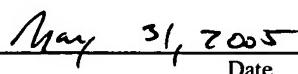
May 31, 2005

Date of Deposit

Adrian Villarreal

Name of Person Mailing Correspondence

  
Signature

  
May 31, 2005  
Date